查询ADG1404供应商

捷多邦,专业PCB打样工厂,24小时加急出货

ANALOG DEVICES

2Ω Max On Resistance, ±15 V/12 V/±5 V 4:1 *i*CMOS[™] Multiplexer

Preliminary Technical Data

ADG1404

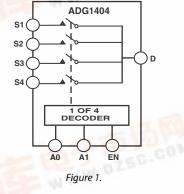
FEATURES

2Ω Max On Resistance 0.5Ω Max On Resistance Flatness 200mA Continuous current 33 V supply range Fully specified at +12 V, ±15 V, ±5 V No V_L supply required 3 V logic-compatible inputs Rail-to-rail operation 14-lead TSSOP and 16-lead LFCSP

APPLICATIONS

Automatic test equipment Data aquisition systems Battery-powered systems Sample-and-hold systems Audio signal routing Communication systems Relay Replacement

FUNCTIONAL BLOCK DIAGRAM



GENERAL DESCRIPTION

The ADG1404 is a complementary metal-oxide semiconductor (CMOS) analog multiplexer, comprising four single channels designed on an *i*CMOS process. *i*CMOS (industrial CMOS) is a modular manufacturing process that combines high voltage CMOS and bipolar technologies. It enables the development of a wide range of high performance analog ICs capable of 33 V operation in a footprint that no previous generation of high voltage parts has been able to achieve. Unlike analog ICs using conventional CMOS processes, *i*CMOS components can tolerate high supply voltages while providing increased performance, dramatically lower power consumption, and reduced package size.

The on resistance profile is very flat over the full analog input range ensuring excellent linearity and low distortion when switching audio signals.

*i*CMOS construction ensures ultralow power dissipation, making the parts ideally suited for portable and batterypowered instruments. The ADG1404 switches one of four inputs to a common output, D, as determined by the 3-bit binary address lines, A0, A1, and EN. Logic 0 on the EN pin disables the device. Each switch conducts equally well in both directions when on and has an input signal range that extends to the supplies. In the off condition, signal levels up to the supplies are blocked. All switches exhibit break-before-make switching action. Inherent in the design is low charge injection for minimum transients when switching the digital inputs.

PRODUCT HIGHLIGHTS

- 1. 2Ω Max On Resistance over temperature.
- 2. Minimum distortion
- 3. 3 V logic-compatible digital inputs: $V_{IH} = 2.0 \text{ V}, V_{IL} = 0.8 \text{ V}$
- 4. No V_L logic power supply required.
- 5. Ultralow power dissipation: <0.03 μ W.
- 6. 14-lead TSSOP and 16-lead 4 mm \times 4 mm LFCSP package.

Reversor Information furnished by Analog Devices is believed to be accurate and reliable.

for the second of the second o

One Technology Way, P.O. Box 9106, Norwood, MA 02062-9106, U.S.A. Tel: 781.329.4700 www.analog.com

Preliminary Technical Data

TABLE OF CONTENTS

Specifications	3
Dual Supply	3
Single Supply	5
Absolute Maximum Ratings	7
Truth Table	8
ESD Caution	7

REVISION HISTORY

Pin Configurations and Function Descriptions	8
Terminology	9
Typical Performance Characteristics	
Test Circuits	
Outline Dimensions	15
Ordering Guide	

SPECIFICATIONS

DUAL SUPPLY

 V_{DD} = 15 V \pm 10%, V_{SS} = –15 V \pm 10%, GND = 0 V, unless otherwise noted.

Table 1.

	25°C	-40°C to + 85°C	-40°C to + 125°C		
ANALOG SWITCH					
Analog Signal Range			V_{DD} to V_{SS}	V	
On Resistance (R _{ON})	1.5			Ωtyp	$V_s = \pm 10 V$, $I_s = -10 mA$; Figure 21
		2		Ωmax	$V_{DD} = +13.5 V, V_{SS} = -13.5 V$
On Resistance Match Between Channels (ΔR _{ON})	0.1			Ωtyp	$V_s = \pm 10 V$, $I_s = -10 mA$
		0.5		Ωmax	
On Resistance Flatness (R _{FLAT(ON)})	0.1			Ωtyp	$V_s = -5 V, 0 V, +5 V; I_s = -10 mA$
		0.5		Ωmax	
LEAKAGE CURRENTS					$V_{DD} = +16.5 V, V_{SS} = -16.5 V$
Source Off Leakage, Is (Off)	±0.01			nA typ	$V_{s} = \pm 10 V$, $V_{s} = \pm 10 V$; Figure 22
3 • • • •	±0.5	±2.5	±5	nA max	v3 = ±10 v, v3 = +10 v, Hgare 22
Drain Off Leakage, I _D (Off)	±0.01			nA typ	$V_{c} = \pm 10 V V_{c} = \pm 10 V_{c}$ Elauro 22
	±0.5	±2.5	±5	nA max	$V_{\text{S}}=\pm10$ V, $V_{\text{s}}=\mp10$ V ; Figure 22
Channel On Leakage, I _D , I _S (On)	±0.5 ±0.04	±2.3	±3		$V_{c} = V_{c} = \pm 10 V_{c}$ Figure 22
Charliner On Leakage, ID, IS (OII)		±2.5	+5	nA typ nA max	$V_s = V_D = \pm 10 \text{ V}$; Figure 23
DIGITAL INPUTS	±1	±2.3	±5	HA HIdX	
			20	V min	
Input High Voltage, VINH			2.0 0.8	V min V max	
Input Low Voltage, V _{INL}	0.005		0.8	-	
Input Current, I _{INL} or I _{NH}	0.005			µA typ	V _{IN} = V _{INL} or V _{INH}
	2.5		±0.5	μA max	
Digital Input Capacitance, CIN	2.5			pF typ	
DYNAMIC CHARACTERISTICS ¹	120				
Transition Time, trrans	120	200	200	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	150	200	200	ns max	$V_s = +10 V$; Figure 24
t _{on} (EN)	70	110	110	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	85	110	110	ns max	$V_s = +10 V$; Figure 24
t _{off} (EN)	90	155	155	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
Dreak Defere Males These Dala	110	155	155	ns max	$V_{s} = +10 V$; Figure 24
Break-Before-Make Time Delay, t _D	25	10	10	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	50	10	10	ns min	$V_{51} = V_{52} = 10$ V; Figure 25
Charge Injection	50			pC typ	$V_s = 0 V, R_s = 0 \Omega, C_L = 1 nF;$ Figure 26
Off Isolation	50			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 27
Channel-to-Channel Crosstalk	60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 28
Total Harmonic Distortion + Noise	0.01			% typ	$R_L = 110 \Omega$, 5 V rms, f = 20 Hz to 20 kHz
–3 dB Bandwidth	50			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; Figure 29
Insertion Loss	0.17			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 29
Cs (Off)	35			pF typ	$f = 1 MHz; V_S = 0 V$
a (a)				pF max	$f = 1 MHz; V_S = 0 V$
C _D (Off)	100			pF typ	$f = 1 MHz; V_S = 0 V$
				pF max	$f = 1 MHz; V_s = 0 V$
C _D , C _s (On)	150			pF typ	$f = 1 MHz; V_s = 0 V$
				pF max	$f = 1 MHz; V_s = 0 V$
POWER REQUIREMENTS					$V_{DD} = +16.5 V, V_{SS} = -16.5 V$
I _{DD}	0.001	1		μA typ	Digital inputs = $0 V \text{ or } V_{DD}$

Preliminary Technical Data

	25°C	-40°C to + 85°C	-40°C to + 125°C		
			1	μA max	
I _{DD}	150			μA typ	Digital inputs = 5 V
			300	μA max	
Iss	0.001			μA typ	Digital inputs = 0 V, 5V or V_{DD}
			1	μA max	
V _{DD} /V _{SS}			±4.5/±16.5	V	Gnd = 0V
				min/max	

¹ Guaranteed by design, not subject to production test.

SINGLE SUPPLY

 V_{DD} = 12 V ± 10%, V_{SS} = 0 V, GND = 0 V, unless otherwise noted.

Table 2.

	25°C	–40°C to +85°C	-40°C to +125°C		
ANALOG SWITCH					
Analog Signal Range			$0 V to V_{\text{DD}}$	V	
On Resistance (R _{ON})	2.5			Ωtyp	$V_s = 10 V$, $I_s = -10 mA$; Figure 21
	3	4		Ω max	$V_{DD} = +10.8 V, V_{SS} = 0 V$
On Resistance Match Between	0.1			Ωtyp	$V_s = 10 V$, $I_s = -10 mA$
Channels (ΔR_{ON})				$\Omega \max$	
On Resistance Flatness (R _{FLAT(ON)})	0.1			Ωtyp	V _s = 3 V, 6 V, 9 V; I _s = −10 mA
					$V_{DD} = 13.2 V$
Source Off Leakage, I _s (Off)	±0.01			nA typ	$V_{\rm S} = 1 \text{ V}/10 \text{ V}, \text{ V}_{\rm D} = 10 \text{ V}/1 \text{ V};$ Figure 22
Source on Leakage, is (on)	±0.5	±2.5	±5	nA max	v ₃ = 1 v/10 v, v ₀ = 10 v/1 v, 1gare 22
Drain Off Leakage, I _D (Off)	±0.01	±2.5	±5	nA typ	$V_{s} = 1 \text{ V}/10 \text{ V}, V_{D} = 10 \text{ V}/1 \text{ V};$ Figure 22
	±0.5	±2.5	±5	nA max	
Channel On Leakage, I _D , I _S (On)	±0.04	12.5	±5	nA typ	$V_s = V_D = 1$ V or 10 V; Figure 23
Charmer on Leakage, 10, 15 (Oh)	±0.04	±2.5	±5	nA max	vs = vb = 1 v or 10 v, rigure 25
DIGITAL INPUTS	<u> </u>	<u> </u>	<u> </u>	TIT THAN	
Input High Voltage, VINH			2.0	V min	
Input Low Voltage, VINH			0.8	V max	
Input Current, Inc or Inn	0.001		0.8	μA typ	VIN = VINL OF VINH
	0.001		±0.5	μΑ typ μΑ max	VIN - VINE OF VINH
Digital Input Capacitance, C _№	2.5		±0.5		
	2.5			pF typ	
	150			nc tun	P = 300 O C = 35 pF
Transition Time, t _{TRANS}	150		265	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	190		265	ns max	$V_{\rm s} = 8 V;$ Figure 24
t _{on} (EN)	95		170	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	120		170	ns max	$V_{\rm S} = 8 V$; Figure 24
t _{off} (EN)	100		170	ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	125		170	ns max	$V_{\rm S} = 8 \text{V}; \text{Figure 24}$
Break-Before-Make Time Delay, t _D	50			ns typ	$R_L = 300 \Omega, C_L = 35 pF$
	50		10	ns min	$V_{S1} = V_{S2} = 8 V$; Figure 25
Charge Injection	50			pC typ	$V_s = 6 V, R_s = 0 \Omega, C_L = 1 nF;$ Figure 26
Off Isolation	50			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 27
Channel-to-Channel Crosstalk	60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; Figure 28
–3 dB Bandwidth	50			MHz typ	$R_L = 50 \Omega$, $C_L = 5 pF$; Figure 29
Cs (Off)	35			pF typ	$f = 1 MHz; V_s = 6V$
				pF max	$f = 1 MHz; V_s = 6V$
C _D (Off)	100			pF typ	$f = 1 MHz; V_s = 6 V$
				pF max	$f = 1 MHz; V_s = 6 V$
C _D , C _s (On)	150			pF typ	$f = 1 MHz; V_s = 6 V$
				pF max	$f = 1 MHz; V_s = 6 V$
POWER REQUIREMENTS					$V_{DD} = 13.2 \text{ V}$
l _{DD}	0.001			μA typ	Digital inputs = 0 V or V _{DD}
			1	μA max	
I _{DD}	150			μA typ	Digital inputs = 5 V
			300	μA max	
V _{DD}			5/16.5	V	Gnd = 0V, Vss = 0V
				min/max	

¹ Guaranteed by design, not subject to production test.

DUAL SUPPLY

 V_{DD} = 5 V \pm 10%, V_{SS} = -5 V \pm 10%, GND = 0 V, unless otherwise noted.

Table 3.

Table 3.		−40°C to	−40°C to		
	25°C	+85°C	+125°C	Unit	Test Conditions/Comments
ANALOG SWITCH					
Analog Signal Range			0 V to V _{DD}	v	
On Resistance (R _{ON})	4			Ωtyp	$V_s = \pm 3.3V$, $I_s = -10$ mA; See figure x
	5			Ω max	$V_{DD} = +4.5 V, V_{SS} = -4.5 V$
On Resistance Match Between	0.1			Ωtyp	$V_s = \pm 3.3 V$, $I_s = -10 mA$
Channels (ΔR_{ON})					
				Ω max	
On Resistance Flatness (R _{FLAT(ON)})	0.1			Ωtyp	$V_s = -3 V/0 V/+3 V$; $I_s = -10 mA$
LEAKAGE CURRENTS					$V_{DD} = +5.5 \text{ V}, \text{ V}_{SS} = -5.5 \text{ V}$
Source Off Leakage, Is (Off)	±0.01			nA typ	$V_s = \pm 4.5 \text{ V}, V_D = \mp 4.5 \text{ V}; \text{ See figure x}$
	±0.5	±2.5	±5	nA max	
Drain Off Leakage, I _D (Off)	±0.01			nA typ	$V_s = \pm 4.5V$, $V_D = \mp 4.5V$; See figure x
	±0.5	±2.5	±5	nA max	
Channel On Leakage, I _D , I _S (On)	±0.04	-		nA typ	$V_s = V_D = \pm 4.5V$; See figure x
<u> </u>	±1	±5	±5	nA max	
DIGITAL INPUTS					
Input High Voltage, V _{INH}			2.0	V min	
Input Low Voltage, VINL			0.8	V max	
Input Current, I _{INL} or I _{INH}	0.001			μA typ	$V_{IN} = V_{INL}$ or V_{INH}
			±0.5	μA max	
Digital Input Capacitance, C _{IN}	3			pF typ	
DYNAMIC CHARACTERISTICS ¹					
Transition Time, trrans	150			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	190		265	ns max	$V_s = 3 V$; Figure 24
ton (EN)	95			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	120		170	ns max	$V_s = 3 V$; Figure 24
t _{off} (EN)	100			ns typ	$R_L = 300 \Omega$, $C_L = 35 pF$
	125		170	ns max	V _s = 3 V; Figure 24
Break-Before-Make Time Delay, t _D	50			ns typ	$R_L = 300 \ \Omega$, $C_L = 35 \ pF$
			10	ns min	$V_{S1} = V_{S2} = 8 V$; See figure x
Charge Injection	50			pC typ	$V_s = 0 V$, $R_s = 0 \Omega$, $C_L = 1 nF$; See figure x
Off Isolation	50			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; See figure
Channel-to-Channel Crosstalk	60			dB typ	$R_L = 50 \Omega$, $C_L = 5 pF$, $f = 1 MHz$; See figure
-3 dB Bandwidth	50			MHz typ	x R _L = 50 Ω , C _L = 5 pF; See figure x
C _s (Off)	35			pF typ	$V_{s} = 0V, f = 1 \text{ MHz}$
	55			pF max	$V_s = 0V, f = 1 \text{ MHz}$ $V_s = 0V, f = 1 \text{ MHz}$
C _D (Off)	35			pF typ	$V_s = 0V$, $f = 1$ MHz
	55			pF max	$V_s = 0V$, $f = 1$ MHz
C _D , C _s (On)	150			pF typ	$V_s = 0V$, $f = 1$ MHz
-5, -3 ()				pF max	$V_s = 0V, f = 1 MHz$ $V_s = 0V, f = 1 MHz$
POWER REQUIREMENTS				P	$V_{DD} = 5.5 V$, $V_{SS} = -5.5 V$
IDD	0.001			μA typ	Digital inputs = $0 V$, $5V \text{ or } V_{DD}$
-00			1	μA max	
V _{DD} /V _{SS}			±4.5/±16.5	V	Gnd = 0V
				min/max	

ABSOLUTE MAXIMUM RATINGS

¹ Guaranteed by design, not subject to production test.

 $T_A = 25^{\circ}C$, unless otherwise noted.

Table 4.

Parameter	Rating
V _{DD} to V _{SS}	35 V
V _{DD} to GND	–0.3 V to +25 V
Vss to GND	+0.3 V to -25 V
Analog Inputs ¹	V_{SS} – 0.3 V to V_{DD} + 0.3 V
Digital Inputs	GND – 0.3 V to V _{DD} + 0.3 V or 30 mA, whichever occurs first
Peak Current, S or D	300 mA (pulsed at 1 ms, 10% duty cycle max)
Continuous Current, S or D	200 mA
Operating Temperature Range	
Automotive (Y Version)	-40°C to +125°C
Storage Temperature Range	–65°C to +150°C
Junction Temperature	150℃
16-Lead TSSOP, θ _{JA} Thermal Impedance	150.4°C/W
16-Lead LFCSP, θ _{JA} Thermal Impedance	72.7°C/W
Reflow Soldering Peak Temperature, Pb free	260°C

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those listed in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability. Only one absolute maximum rating may be applied at any one time.

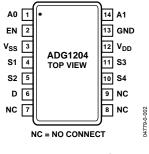
¹ Overvoltages at IN, S, or D are clamped by internal diodes. Current should be limited to the maximum ratings given.

ESD CAUTION

ESD (electrostatic discharge) sensitive device. Electrostatic charges as high as 4000 V readily accumulate on the human body and test equipment and can discharge without detection. Although this product features proprietary ESD protection circuitry, permanent damage may occur on devices subjected to high energy electrostatic discharges. Therefore, proper ESD precautions are recommended to avoid performance degradation or loss of functionality.



PIN CONFIGURATIONS AND FUNCTION DESCRIPTIONS



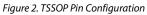


Table 5. Pin Function Descriptions

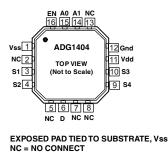


Figure 3. LFCSP Pin Configuration

Pin	No.		
TSSOP	LFCSP	Mnemonic	Description
1	15	A0	Logic Control Input.
2	16	EN	Active High Digital Input. When low, the device is disabled and all switches are off. When high, Ax logic inputs determine on switches.
3	1	Vss	Most Negative Power Supply Potential.
4	3	S1	Source Terminal. Can be an input or an output.
5	4	S2	Source Terminal. Can be an input or an output.
6	6	D	Drain Terminal. Can be an input or an output.
7 to 9	2,5,7,8, 13	NC	No Connection.
10	9	S4	Source Terminal. Can be an input or an output.
11	10	S3	Source Terminal. Can be an input or an output.
12	11	V _{DD}	Most Positive Power Supply Potential.
13	12	GND	Ground (0 V) Reference.
14	14	A1	Logic Control Input.

TRUTH TABLE

Table 6.

EN	A1	A0	S1	S2	S3	S4
0	Х	Х	Off	Off	Off	Off
1	0	0	On	Off	Off	Off
1	0	1	Off	On	Off	Off
1	1	0	Off	Off	On	Off
1	1	1	Off	Off	Off	On

ADG1404

TERMINOLOGY

 \mathbf{I}_{DD}

The positive supply current.

Iss

The negative supply current.

 $V_{\rm D}\left(V_{S}\right)$ The analog voltage on Terminals D and S.

R_{ON} The ohmic resistance between D and S.

 $\mathbf{R}_{\text{FLAT(ON)}}$ Flatness is defined as the difference between the maximum and minimum value of on resistance, as measured over the specified analog signal range.

Is (Off) The source leakage current with the switch off.

I_D (Off) The drain leakage current with the switch off.

 $I_{\rm D},\,I_{\rm S}\left(On\right)$ The channel leakage current with the switch on.

 $\label{eq:Vinl} V_{\text{INL}}$ The maximum input voltage for Logic 0.

 $V_{\mbox{\scriptsize INH}}$ The minimum input voltage for Logic 1.

 $I_{\text{INL}}\left(I_{\text{INH}}\right)$ The input current of the digital input.

 C_s (Off) The off switch source capacitance, which is measured with reference to ground.

 C_D (Off) The off switch drain capacitance, which is measured with reference to ground. C_D , C_s (On) The on switch capacitance, which is measured with reference to ground.

C_{IN} The digital input capacitance.

t_{ON} **(EN)** The delay between applying the digital control input and the output switching on. See Figure 24, Test Circuit 4.

t_{OFF} **(EN)** The delay between applying the digital control input and the output switching off.

Charge Injection A measure of the glitch impulse transferred from the digital input to the analog output during switching.

Off Isolation A measure of unwanted signal coupling through an off switch.

Crosstalk A measure of unwanted signal that is coupled through from one channel to another as a result of parasitic capacitance.

Bandwidth The frequency at which the output is attenuated by 3 dB.

On Response The frequency response of the on switch.

Insertion Loss The loss due to the on resistance of the switch.

THD + N The ratio of the harmonic amplitude plus noise of the signal to the fundamental.

t_{TRANS}

The delay time between the 50% and 90% points of the digital input and switch on condition when switching from one address state to another.

TYPICAL PERFORMANCE CHARACTERISTICS



Figure 4. On Resistance as a Function of V_D (V_S) for Single Supply

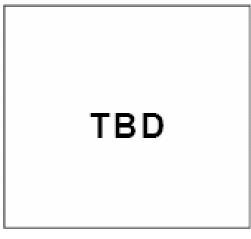


Figure 5. On Resistance as a Function of V_D (V_S) for Dual Supply

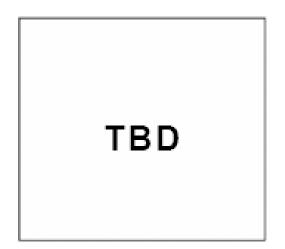


Figure 6. On Resistance as a Function of $V_{\rm D}$ (Vs) for Different Temperatures, Dual Supply

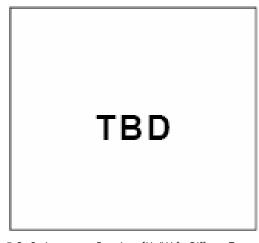


Figure 7. On Resistance as a Function of $V_{\rm D}\,(V_{\rm S})$ for Different Temperatures, Single Supply

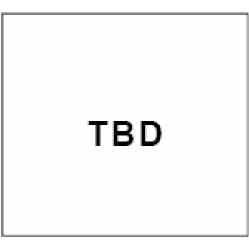


Figure 8. Leakage Currents as a Function of Temperature for Dual Supply

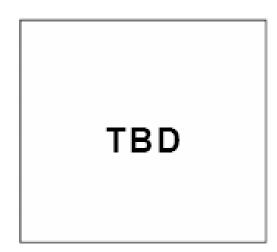


Figure 9. Leakage Currents as a Function of Temperature for Single Supply



Figure 10. Logic Threshold Voltage vs Supply Voltage

Figure 13. Transition Times vs. Temperature

TBD

TBD

Figure 11. IDD vs. Logic Level



Figure 12. Charge Injection vs. Source Voltage

Figure 14. Off Isolation vs. Frequency

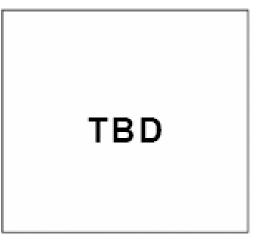


Figure 15. Crosstalk vs. Frequency



Figure 16. On Response vs. Frequency



Figure 17. THD + N vs. Frequency

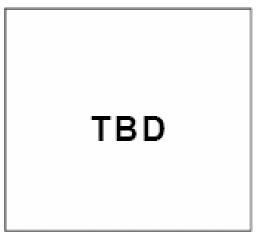


Figure 19. On Capacitance vs. Source Voltage

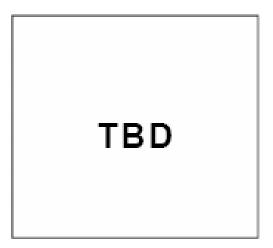


Figure 20. Capacitance vs. Source Voltage for Single Supply

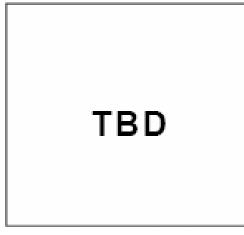


Figure 18. Off Capacitance vs. Source Voltage

ADG1404

TEST CIRCUITS

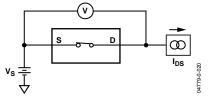
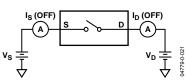


Figure 21. Test Circuit 1—On Resistance



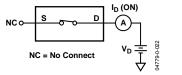


Figure 22. Test Circuit 2—Off Leakage

Figure 23. Test Circuit 3—On Leakage

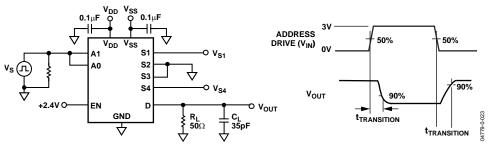


Figure 24. Test Circuit 4—Address to Output Switching Times

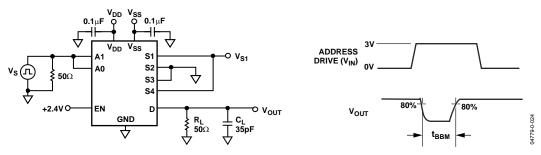


Figure 25. Test Circuit 5—Break-Before-Make Time

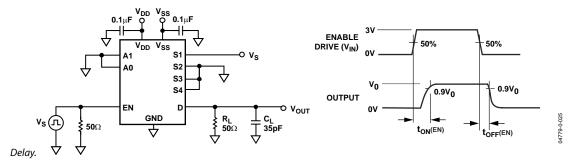
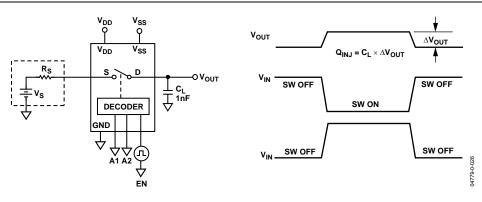
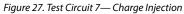
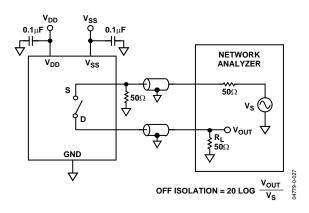


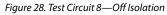
Figure 26. Test Circuit 6—Enable-to-Output Switching Delay

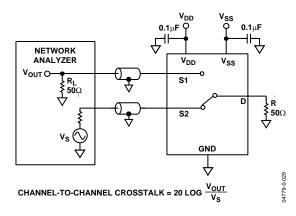
Preliminary Technical Data

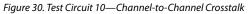












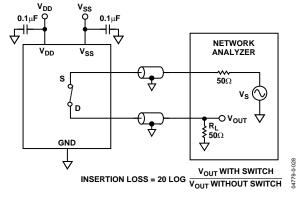


Figure 29. Test Circuit 9—Bandwidth

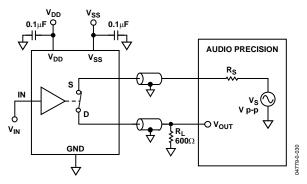


Figure 31. Test Circuit 11—THD + Noise

OUTLINE DIMENSIONS

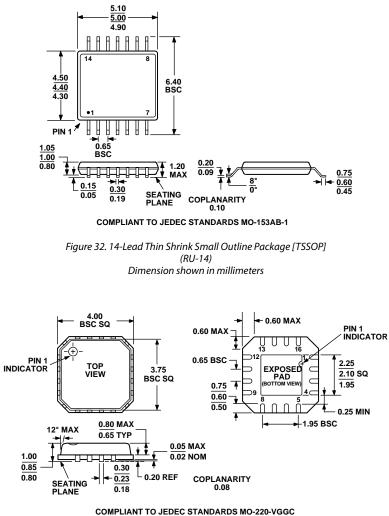


Figure 33. 16-Lead Lead Frame Chip Scale Package [VQ_LFCSP] 4 mm × 4 mm Body, Very Thin Quad (CP-16-4) Dimensions shown in millimeters

ORDERING GUIDE

Model	Temperature Range	Package Description	Package Option
ADG1404YRUZ ¹	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-14
ADG1404YRUZ-REEL ¹	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-14
ADG1404YRUZ-REEL71	-40°C to +125°C	Thin Shrink Small Outline Package (TSSOP)	RU-14
ADG1404YCPZ-500RL71	-40°C to +125°C	Lead Frame Chip Scale Package (VQ_LFCSP)	CP-16-4
ADG1404YCPZ-REEL71	-40°C to +125°C	Lead Frame Chip Scale Package (VQ_LFCSP)	CP-16-4

 1 Z = Pb-free part.

NOTES

© 2007 Analog Devices, Inc. All rights reserved. Trademarks and

registered trademarks are the property of their respective owners.

NOTES



www.analog.com

ADG1404